

Third edition  
2020-10

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# Information technology — Radio frequency identification device performance test methods —

## Part 3: Test methods for tag performance

*Technologies de l'information — Méthodes d'essai des performances  
du dispositif d'identification par radiofréquence —*

*Partie 3: Méthodes d'essai des performances du tag*



Reference number  
ISO/IEC 18046-3:2020(E)

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Published in Switzerland

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## Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see [www.iso.org/iso/foreword.html](http://www.iso.org/iso/foreword.html).

This document was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 31, *Automatic identification and data capture techniques*.

This third edition cancels and replaces the second (ISO/IEC 18046-3:2012), which has been technically revised.

The main changes compared to the previous edition are as follows:

- Change of the frequency range to 860 MHz to 930 MHz, as no countries, including Japan, support a frequency in the 930 MHz to 960 MHz range anymore;
- Adaptation of the test method for 860 MHz to 930 MHz band based on 10 years experience of the use of this document.

A list of all parts in the ISO/IEC 18046 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at [www.iso.org/members.html](http://www.iso.org/members.html).

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## Introduction

Radio frequency identification (RFID) technology has broad applicability to the automatic identification and data capture (AIDC) industry in item management. As a wireless communication technique based on radio frequency technology, the applications cover multiple levels of the industrial, commercial and retail supply chains. These can include:

- freight containers,
- returnable transport items (RTI),
- transport units,
- product packaging, and
- product tagging.

Performance tests define test methods which deliver results that allow the comparison of different RFID systems, interrogators and tags in order to select among them for use in a particular application.

The performance characteristics of devices (tags and interrogation equipment) can vary drastically due to application factors as well as the particular RFID air interface (frequency, modulation, protocol, etc.) being supported. Of key concern is the matching of the various performance characteristics to the user application. Additionally, in an open environment, users of such technology demand multiple sources for these devices from technology providers. A key challenge is a method of evaluating the differences between various technology providers' products in a consistent and equitable manner.

This document provides a framework for meeting the above noted concerns and challenges. To this end, clear definitions of performance as related to user application of RFID technology in the supply chain are provided. Based on such application-based definitions, test methods are defined with attention to the test parameters required for a consistent evaluation of RFID devices.

Of particular significance, these tests are defined for RFID devices with one antenna. It is common practice to have products with both single and multiple antennae to define an RFID transaction zone sufficient for the application. The defined test methods used are for a single antenna but can equivalently be extended to equipment with multiple antennae, in order to evaluate performance under conditions more closely matching those of a particular application. However, it is important to exercise care in multiple-antenna measurement since multiple antennae can cause antenna-to-antenna interactions, physical packaging limitations, mutual coupling issues, shadowing issues, directivity issues and other impacts, even with respect to interrogators since these can be limited in size, shape and mounting method for many RFID applications.